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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Tsao, Yi-Chang; et al.) Examiner: Gabor, Otilia
)
Serial No.: 10/607,607) Art Unit: 2878
)
Filed: June 27, 2003) Our Ref: B-5136 621042-5
)
For: "APPARATUS AND METHOD FOR) Date: June 9, 2005
INSPECTING CRYSTAL QUALITY OF)
A POLYSILICON FILM") Re: <i>Amendment and Response</i>
)

AMENDMENT AND RESPONSE

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

This is in reply to the non-final Office Action mailed on March 10, 2005, an initial response to which is due no later than

June 10, 2005.

Please amend the above-identified application as described below and consider the following remarks. **All amendments and remarks herein are made without prejudice.**

Amendments to the Specification begin on page 2 of this paper.

Remarks/Arguments begin on page 3 of this paper.